



THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Frum et al.	Group Art Unit: N/A
Application No: 10/615,159	Examiner: Unknown
Confirmation No: Unknown	Attorney Docket No: 007352 USA/ETCH/DRIE/JB
Filed: 07/07/2003	March 29 2004 San Francisco, California
Title: INTERFEROMETRIC ENDPOINT DETECTION IN A SUBSTRATE ETCHING PROCESS	

INFORMATION DISCLOSURE STATEMENT

Mail Stop Non-Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir/Madam:

Attached hereto is a PTO-1449 form listing documents believed relevant to the subject application. It is respectfully requested that these documents be considered by the Examiner and an initialed copy of the form be returned to the undersigned.

Applicant believes that the Office should consider this Information Disclosure Statement because it is being filed before the mailing of a first Office Action on the merits.

It is believed that no fee is due for the filing of this Information Disclosure Statement. However, if any fee is due, the Commissioner is hereby authorized to charge payment of any such fees to Deposit Account No. 10-0258.

Also, if any Petition is required for the filing of this Information Disclosure Statement, such Petition is requested herein.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to:

Mail Stop Non-Fee Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

By: J. Taylor Branche

J. Taylor Branche

Date of Deposit: March 29, 2004

It is believed that this disclosure complies with the requirements of 37 C.F.R. §§ 1.56, 1.97, and 1.98, and the Manual of Patent Examining Procedures § 707.05(b). If for some reason the Examiner considers otherwise, it is respectfully requested that the undersigned be called so that any deficiencies can be remedied.

It should be noted that the word "prior" has been deleted from the attached PTO-1449 form(s).

A copy of each foreign patent document and relevant art (not including US Patents and application publications) is enclosed.

Some of the documents have markings thereon. No significance is meant to be attached to the markings.

With regard to any translations which may be provided here
These documents are not necessarily analogous.

Respectfully submitted,
JANAH & ASSOCIATES, P.C.

Date: March 29, 2004

By: 

Ashok K. Janah
Reg. No. 37,487

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Patent Department, M/S 2061
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Santa Clara, California 95052

Encl.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

DOCKET NO: 007352 USA/ETCH/DRIE/JB

APPLICATION NO.:
10/615,159INFORMATION DISCLOSURE STATEMENT
IN AN APPLICATION

APPLICANT: Frum et al.

FILING DATE: 7/7/2003

GROUP ART UNIT:
1763

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	3	6	1	2	6	9	2	10/12/1971	Kruppa, et al.			
	3	8	2	4	0	1	7	04/01/1975	Galyon			
	3	8	7	4	7	9	7	04/01/1975	Kasai			
	3	9	8	5	4	4	7	10/12/1976	Kruppa, et al.			
	4	1	4	1	7	8	0	02/27/1979	Kleinknecht, et al.			
	4	1	9	8	2	6	1	04/15/1980	Busta, et al.			
	4	2	0	8	2	4	0	06/17/1980	Latos			
	4	3	1	7	6	9	8	03/02/1982	Christol, et al.			
	4	3	2	8	0	6	8	05/04/1982	Curtis			
	4	3	6	7	0	4	4	01/04/1983	Booth, Jr, et al			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
												YES	NO
	0	5	1	1	4	4	8	11/4/1992	EP Application				
	0	7	5	3	9	1	2	01/15/1997	EP Application				
	2	2	9	3	7	9	5	04/10/1996	Great Britain				
	0	7	0	9	8	7	7	05/01/1996	EP Application			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	PCT International Search Report dated September 2, 1999
	European Search Report dated September 4, 2001, P.B. 5818- Patentlaan 2, 2280 HV Rijswijk (ZH), The Hague
EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION								DOCKET NO: 007352 USA/ETCH/DRIE/JB				APPLICATION NO.: 10/615,159	
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U.S. PATENT DOCUMENTS												
EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	4	4	5	4	0	0	1	06/12/1984	Sternheim, et al.			
	4	6	1	1	9	1	9	09/16/1986	Brooks, Jr., et al.			
	4	6	1	8	2	6	2	10/21/1986	Maydan, et al.			
	4	8	3	8	6	9	4	06/13/1989	Betz, et al.			
	4	9	2	7	4	8	5	05/22/1990	Cheng, et al.			
	4	9	5	3	9	8	2	09/04/1990	Ebbing, et al.			
	4	9	7	2	9	7	2	11/20/1990	Hauser, et al.			
	5	1	3	1	7	5	2	07/21/1992	Yu, et al.			
	5	1	5	1	5	8	4	09/29/1992	Ebbing, et al.			
	5	3	6	2	3	5	6	11/08/1994	Schoenborn			

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	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
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	5	4	5	0	2	0	5	09/12/1995	Sawin, et al.			
	5	5	0	3	7	0	7	04/02/1996	Maung, et al.			
	5	5	0	4	8	3	0	10/15/1996	Bobel, et al.			
	5	6	5	8	4	1	8	08/19/1997	Coronel, et al.			
	5	7	5	6	4	0	0	05/26/1998	Ye, et al.			
	6	0	8	1	3	3	4	06/27/2000	Grimbergen, et al.			
	6	1	6	5	3	1	1	12/26/2000	Collins, et al.			
	4	1	4	7	4	3	5	04/30/1979	Habegger			
	4	8	4	6	9	2	8	07/11/1989	Dolins, et al.			
	4	8	4	7	7	9	2	07/11/1989	Barna, et al.			

FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
												YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
	Maynard, et al., "Multiwavelength Ellipsometry for Real-time Process Control of the Plasma Etching of Patterned Samples." <u>J. Vac Sci Technol. B</u> , 15 (1), Jan/Feb 1997, pages 109-115
	Klemens, F.P., et al., "High Density Plasma Gate Etching of 0.12 μ m Devices with Sub 1.5 nm Gate-Oxides." <u>Electrochemical Society Proceedings</u> , Volume 97-30, pages 85-95

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		4	8	6	1	4	1	9	08/29/1989		Flinchbaugh, et al.								
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